ERIEZ

食品工業金屬探測工具 Metal Detectable Tools 衛生 環衛 安全 Hygiene | Sanitation | Safety



食品工業金屬探測工具作為物料處理用 **ERIEZ** Metal Detectable Tools for Material Handling.



ERIEZ offers a variety of metal detectable tools for moving small or large amounts of material.

ERIEZ提供了多種金屬檢測工具,移動小或大數量的材料。

As part of a comprehensive line of hygienic material handling tools, **ERIEZ** metal detectable products are made with a specially formulated FDA-compliant polypropylene resin with a semi-ferrous additive so they can be easily identified by standard metal detection equipment.

搬運工具作為衛生材料的全面產品線的一部分,ERIEZ金屬探測產品均採用特殊制定符合FDA標準的聚丙烯樹脂與半鐵添加劑等等,他們可以很容易地確定標準的金屬探測設備。

Designed to minimize the risk of cross-contamination in wet or dry food processing, one-piece construction helps eliminate areas for bacteria to hide and multiply.

以盡量減少在潮濕或乾燥的食品加工交叉污染的風險設計,單件結構有助於消除區域對於細菌隱藏和繁殖。

The products are also chemical resistant and autoclavable, making them a great alternative to stainless steel.

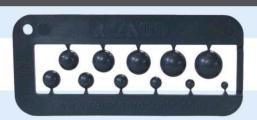
該產品還耐化學腐蝕和高溫高壓滅菌,使之成為一個不銹鋼替代品

Available in a vast array of colors, **ERIEZ** metal detectable products support color-coding programs and hygienic sanitary and safety procedures throughout food processing facilities.

ERIEZ可在色彩繁多金屬探測產品支持彩色編碼項目和衛生在整個食品加工設施的衛生和安全程序

ERIEZ

Metal Detectable 金屬探測 Test Kit 檢測試組件



Allows testing for detectability with specific equipment. 可讓測試探測與特定的設備 What:

Where: In food processing areas where metal detectable tools and

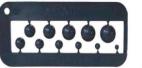
equipment are used. 在食品加工領域的金屬探測工具和設備的使用

Why: Many variables contribute to detectability; provides peace of mind that the tools selected can be properly identified by metal

detection equipment.

許多變數有助於探測;提供安心的選擇的工具,可以通過金屬檢測

設備得到正確的識別



金屬探測檢測試組件 Metal Detectable Test Kit **MDTK**



Brand 品牌	Material 材料	Dimensions 尺寸	FDA Compliant 符合FDA標準
ERIEZ	Polypropylene/	4mm-14mm	Yes
	Semi-ferrous additive	spheres	

The Metal Detectable Test Kit is available to allow testing for detectability with specific equipment. Many variables contribute to detectability.

金屬檢測的檢測試組件可允許測試探測與特定的設備。 許多變數有助於探測。